

Search Notes

Application/Control No.

10/525,934

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

BIESTER, KLAUS

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	920	1/7/2007	DB
	922		
	358		
	394		
	391		
166	338		
	340		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner